# International Rectifier

## **IRF7104**

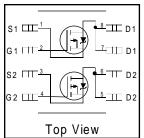
#### HEXFET® Power MOSFET

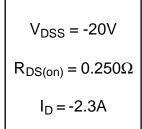
- Adavanced Process Technology
- Ultra Low On-Resistance
- Dual P-Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching

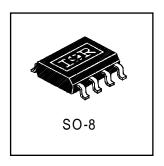
#### Description

Fourth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and dual-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.







#### **Absolute Maximum Ratings**

|                                        | Parameter                                       | Max.         | Units |
|----------------------------------------|-------------------------------------------------|--------------|-------|
| I <sub>D</sub> @ T <sub>A</sub> = 25°C | Continuous Drain Current, V <sub>GS</sub> @ 10V | -2.3         |       |
| $I_D @ T_A = 70^{\circ}C$              | Continuous Drain Current, V <sub>GS</sub> @ 10V | -1.8         | Α     |
| I <sub>DM</sub>                        | Pulsed Drain Current ①                          | -10          |       |
| P <sub>D</sub> @T <sub>C</sub> = 25°C  | Power Dissipation                               | 2.0          | W     |
|                                        | Linear Derating Factor                          | 0.016        | W/°C  |
| V <sub>GS</sub>                        | Gate-to-Source Voltage                          | ± 12         | V     |
| dv/dt                                  | Peak Diode Recovery dv/dt ②                     | -3.0         | V/nS  |
| $T_{J,}T_{STG}$                        | Junction and Storage Temperature Range          | -55 to + 150 | ∞     |

#### **Thermal Resistance Ratings**

|                 | Parameter                     | Min. | Тур. | Max. | Units |
|-----------------|-------------------------------|------|------|------|-------|
| $R_{\theta JA}$ | Maximum Junction-to-Ambient ④ |      |      | 62.5 | °C/W  |

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

|                                 | Parameter                            | Min. | Тур.   | Max. | Units | Conditions                                                           |
|---------------------------------|--------------------------------------|------|--------|------|-------|----------------------------------------------------------------------|
| V <sub>(BR)DSS</sub>            | Drain-to-Source Breakdown Voltage    | -20  |        |      | V     | $V_{GS} = 0V, I_D = -250\mu A$                                       |
| $\Delta V_{(BR)DSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient  |      | -0.015 |      | V/°C  | Reference to 25°C, I <sub>D</sub> = -1mA                             |
| <u> </u>                        | Otatia Busin ta Osama Os Basistanas  |      | 0.19   | 0.25 | Ω     | $V_{GS} = -10V, I_D = -1.0A$ ③                                       |
| R <sub>DS(ON)</sub>             | Static Drain-to-Source On-Resistance |      | 0.30   | 0.40 | 1 12  | V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -0.50A ③                   |
| V <sub>GS(th)</sub>             | Gate Threshold Voltage               | -1.0 |        | -3.0 | V     | $V_{DS} = V_{GS}, I_{D} = -250 \mu A$                                |
| g <sub>fs</sub>                 | Forward Transconductance             |      | 2.5    |      | S     | $V_{DS} = -15V, I_{D} = -2.3A$ ③                                     |
|                                 | Durin to Course Lordon Course        |      |        | -2.0 |       | $V_{DS} = -16V, V_{GS} = 0V$                                         |
| IDSS                            | Drain-to-Source Leakage Current      |      |        | -25  | μA    | V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C |
|                                 | Gate-to-Source Forward Leakage       |      |        | -100 |       | V <sub>GS</sub> = -12V                                               |
| I <sub>GSS</sub>                | Gate-to-Source Reverse Leakage       |      |        | 100  | nA    | V <sub>GS</sub> = 12V                                                |
| Qg                              | Total Gate Charge                    |      | 9.3    | 25   |       | I <sub>D</sub> = -2.3A                                               |
| $Q_{gs}$                        | Gate-to-Source Charge                |      | 1.6    |      | nC    | $V_{DS} = -10V$                                                      |
| $Q_{gd}$                        | Gate-to-Drain ("Miller") Charge      |      | 3.0    |      |       | V <sub>GS</sub> = -10V ③                                             |
| t <sub>d(on)</sub>              | Turn-On Delay Time                   |      | 12     | 40   |       | $V_{DD} = -10V$                                                      |
| t <sub>r</sub>                  | Rise Time                            |      | 16     | 40   | 1     | $I_D = -1.0A$                                                        |
| t <sub>d(off)</sub>             | Turn-Off Delay Time                  |      | 42     | 90   | ns    | $R_G = 6.0\Omega$                                                    |
| t <sub>f</sub>                  | FallTime                             |      | 30     | 50   | 1     | $R_D = 10\Omega$ ③                                                   |
| L <sub>D</sub>                  | Internal Drain Inductance            |      | 4.0    |      | nH    | Between lead,6mm(0.25in.)                                            |
| L <sub>S</sub>                  | Internal Source Inductance           |      | 6.0    |      | 1111  | from package and center of die contact s                             |
| C <sub>iss</sub>                | Input Capacitance                    |      | 290    |      |       | $V_{GS} = 0V$                                                        |
| C <sub>oss</sub>                | Output Capacitance                   |      | 210    |      | pF    | $V_{DS} = -15V$                                                      |
| C <sub>rss</sub>                | Reverse Transfer Capacitance         |      | 67     |      |       | f = 1.0MHz                                                           |

#### **Source-Drain Ratings and Characteristics**

|                 | Parameter                 | Min.        | Тур.                                                                                           | Max. | Units | Conditions                                             |   |                  |
|-----------------|---------------------------|-------------|------------------------------------------------------------------------------------------------|------|-------|--------------------------------------------------------|---|------------------|
| IS              | Continuous Source Current |             |                                                                                                | 2.0  |       | MOSFET symbol                                          |   |                  |
|                 | (Body Diode)              |             |                                                                                                | -2.0 | ٨     | showing the                                            |   |                  |
| I <sub>SM</sub> | Pulsed Source Current     |             |                                                                                                |      |       |                                                        | Α | integral reverse |
|                 | (Body Diode) ①            |             |                                                                                                | -9.2 |       | p-n junction diode.                                    |   |                  |
| $V_{SD}$        | Diode Forward Voltage     | i           |                                                                                                | -1.2 | V     | $T_J = 25^{\circ}C$ , $I_S = -1.25A$ , $V_{GS} = 0V$ ③ |   |                  |
| t <sub>rr</sub> | Reverse Recovery Time     | <del></del> | 69                                                                                             | 100  | ns    | $T_J = 25$ °C, $I_F = -1.25$ A                         |   |                  |
| Qrr             | Reverse RecoveryCharge    |             | 90                                                                                             | 140  | nC    | di/dt = 100A/µs ③                                      |   |                  |
| t <sub>on</sub> | Forward Turn-On Time      | Intr        | Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> ) |      |       |                                                        |   |                  |

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\begin{tabular}{l} @ \ I_{SD} \le -2.3A, \ di/dt \le 100A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_J \le 150 {}^{\circ}C \end{tabular}$
- 4 Surface mounted on FR-4 board,  $t \leq 10 sec.$

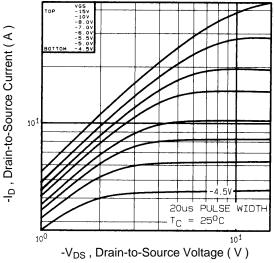


Fig 1. Typical Output Characteristics

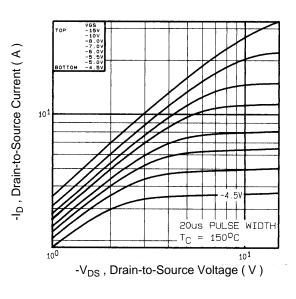


Fig 2. Typical Output Characteristics

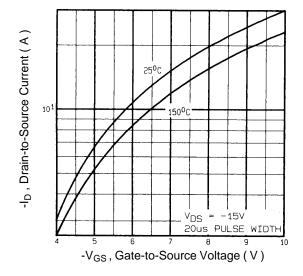
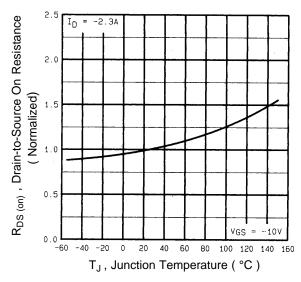
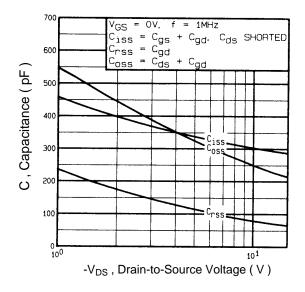


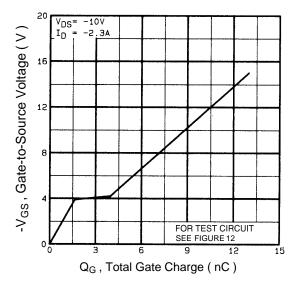
Fig 3. Typical Transfer Characteristics



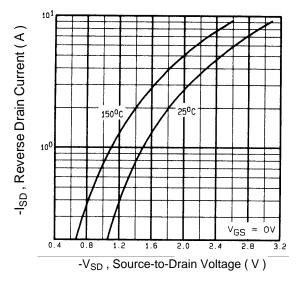
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

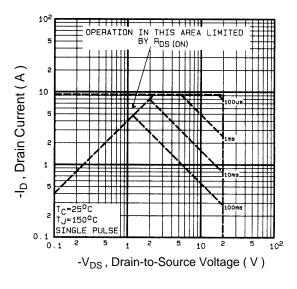
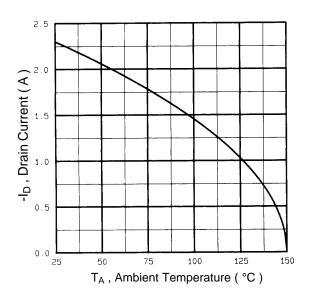


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Ambient Temperature

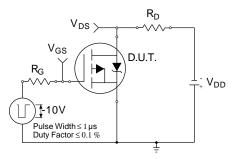


Fig 10a. Switching Time Test Circuit

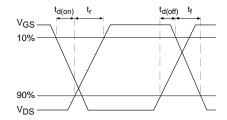


Fig 10b. Switching Time Waveforms

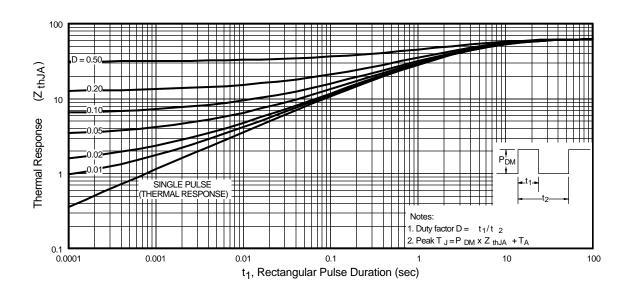


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

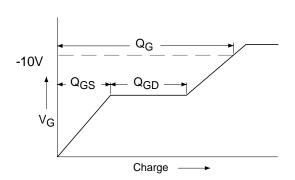


Fig 12a. Basic Gate Charge Waveform

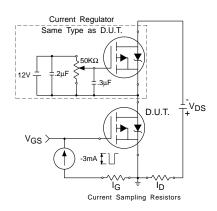
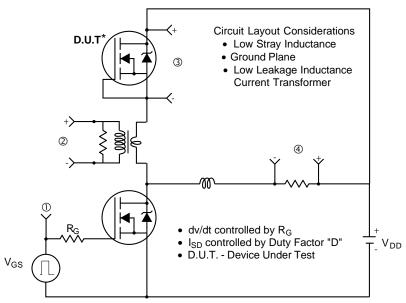
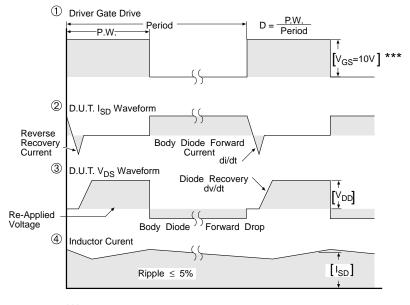


Fig 12b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel

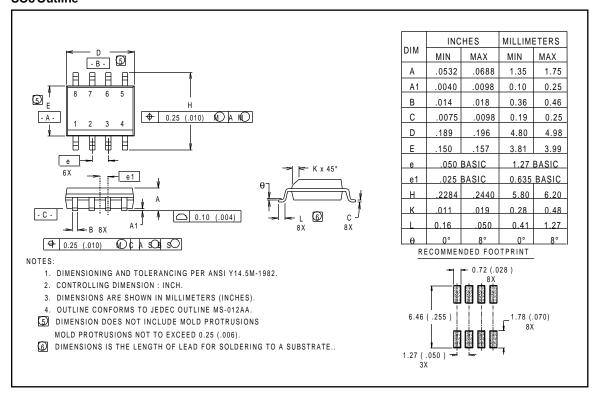


\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

Fig 13. For P-Channel HEXFETS

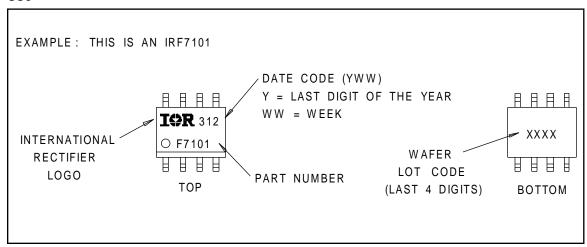
## IRF7104

# Package Outline



#### Part Marking Information

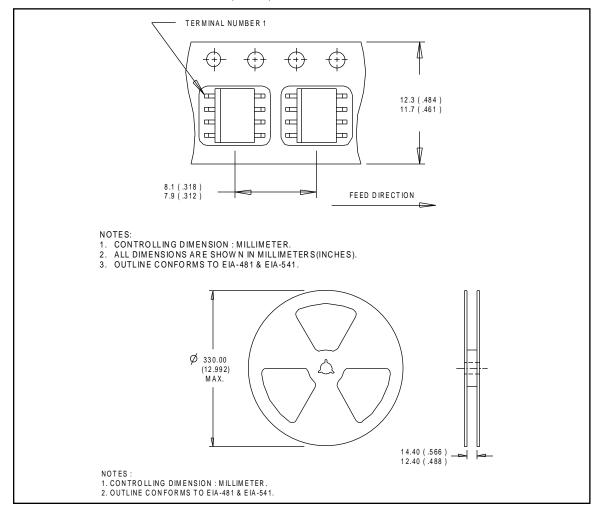
#### **SO8**



### Tape & Reel Information

#### **SO8**

Dimensions are shown in millimeters (inches)



# International TOR Rectifier

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